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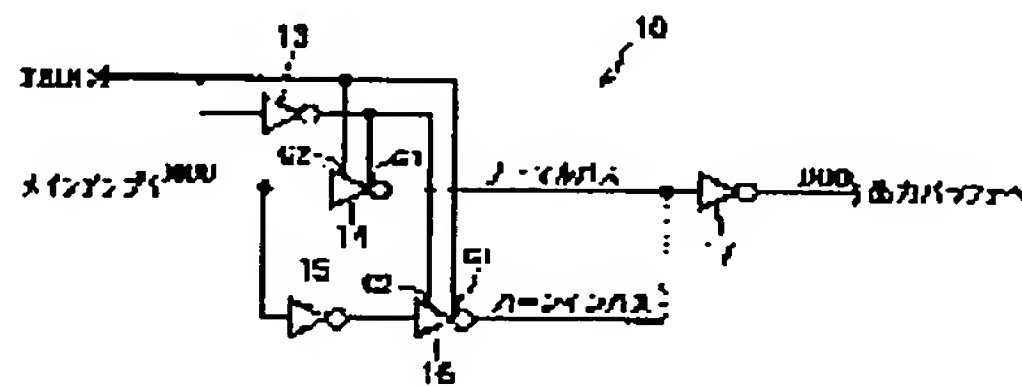
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(54) SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE

(57)Abstract:

PROBLEM TO BE SOLVED: To perform discrimination when a vender test mode is set surely without using a measuring device such as an ammeter and the like.

SOLUTION: When a vender test mode in which a burn-in test is performed is set, a test input signal TBIN of a Hi level is outputted to a normal/burn-in signal output circuit 10 from a test control circuit, an inverter 13 is made a floating state, and an inverter 16 is operated. Therefore, data MO0 outputted from a sense amplifier is outputted to an output buffer as reversed data of data written through inverters 15-17. This reversed data are monitored by a burn-in tester, and it is discriminated that a burn-in test mode is set.



LEGAL STATUS

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